GEKKO

HIGH-RESOLUTION PA FLAW DETECTOR



PAUT MADE EASY

■ UNIQUE SET OF NDT TECHNIQUES

With a 64-channel parallel architecture, GEKKO is the only flaw detector offering conventional UT, standard PAUT, TOFD and real-time Total Focusing Method (TFM).

■ COMPLETE TOOLSET

All GEKKO techniques (UT, TOFD, PAUT, TFM) are available for conventional and phased-array probes as well as dual array probes (linear and matrix). Delay-laws and scan-plans are prepared onboard, avoiding the need to import files from a PC.

READY FOR FIELD INSPECTION

GEKKO meets or exceeds the minimum instrumentation and software requirements specified in ASME, AWS, API, ASTM, ISO-EN standards for code compliant inspections while providing unique means of default characterization. GEKKO is also certified by CSWIP and PCN approved.

■ COMPATIBLE WITH ALL PROBES AND SCANNERS

GEKKO uses IPEX connectors for phased-array UT and LEMO connectors for conventional UT. With up to 3 encoders input, GEKKO offers compatibility with common and advanced scanning devices.



USER-FRIENDLY FLAW DETECTOR

EASY

GEKKO's user-interface is developed to ease the work of operators from level-1 to experts. Using simple yet powerful wizards, users can customize field-ready applications. Thanks to visual libraries and dedicated apps, the risk for errors is reduced while making the inspection easier and faster.



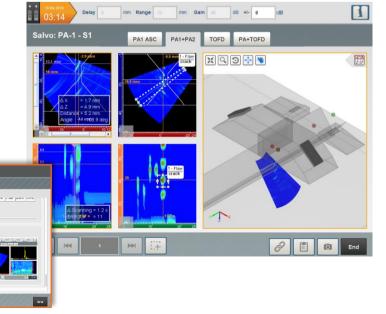


GUIDED

Step-by-step guidance is offered throughout the complete inspection process, including equipment definition, calibration and acquisition. GEKKO offers 3-click calibration tools for probe balancing, material calibration, wedge calibration, TCG and TOFD, for quicker and easier code-compliant inspections.

COMPLETE

With a fast SSD hard-drive, operators can store large inspection files (>10 Gb) and analyze them on the spot using the 10.4" touchscreen. Incremented data saving and automatic reports can be customized and exported as PDF files. Data can also be exported for analysis on a PC using the free viewer provided with GEKKO.



COMPLETE NDT TOOLSET

Some procedures require standard UT, others TOFD or PA. With GEKKO, all UT techniques are included to offer a versatile and field-ready equipment.

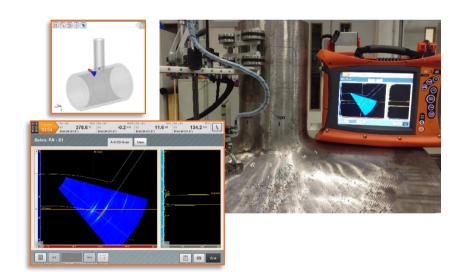
■ WELD INSPECTION

Features such as weld overlays, precise delay-laws, 800% dynamic range and 3D-corrected images ease the diagnostic to detect and size flaws. Combining various techniques and using up to 8 groups in a single pass substantially increases the productivity of inspections. GEKKO is compatible with scanners and accessories from market-leading vendors.



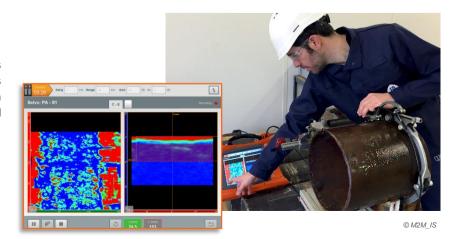
■ NOZZLE INSPECTION

With the possibility to define nozzle type geometries on-board, GEKKO can be used for 3-axis encoded nozzle inspections (scan, index and skew). A real-time cross-section overlay of the nozzle is superimposed on the S-Scan image as the operator scans the specimen.



CORROSION MAPPING

GEKKO can be used with chain-scanners for corrosion mapping. Real-time data is displayed allowing high-resolution corrosion detection. C-Scan amplitude and time of flight are available.



HIGH-RESOLUTION FLAW DETECTOR

For unparalleled resolution detection and characterization, GEKKO offers the real-time Total focusing Method (TFM) imaging.

REAL-TIME TFM

TFM focuses at each point of a user-specified zone for high-resolution imaging and accurate defect characterization. Real-time imaging with high scanning-speed can be achieved, for clear image and defect contouring. The TFM has a 256x256 pixels image resolution (65K points focusing).

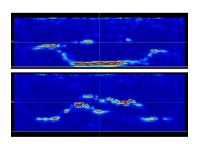
EXTENDED TFM IMAGES

A-B-S-C Scan + 3D views are natively available for standard PA. GEKKO extends these standard NDT views to TFM allowing an operator to use advanced imaging in a familiar environment.

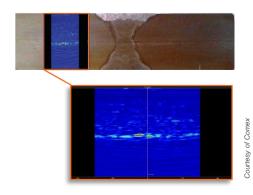


■ HYDROGEN BLISTERING CHARACTERIZATION

- HTHA High Temperature Hydrogen Attack

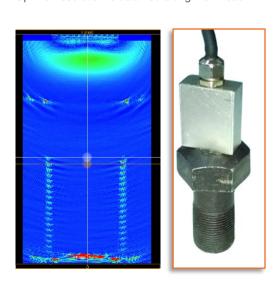


- HIC Small defect detection for carbon steel specimen inspection.



SCREW THREAD INSPECTION

Optimal resolution is obtained along the thread.

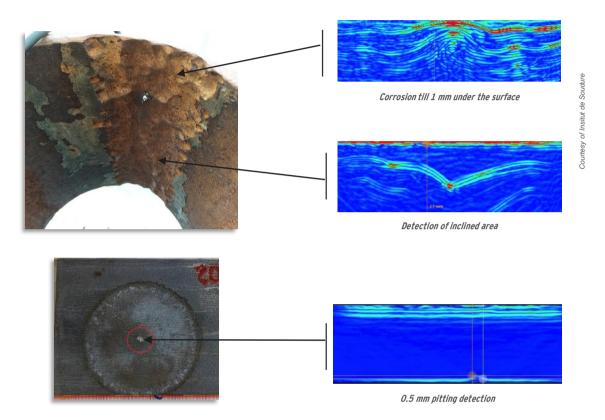


irtesy of Karl Deutsch

HIGH-RESOLUTION FLAW DETECTOR

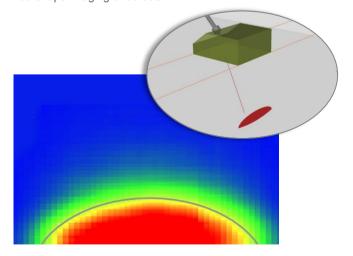
■ REAL-TIME TFM

- Reduced dead zone: detection of corrosion less than 1mm from the front surface.
- Pitting detection smaller than 1 mm



■ TRUE IMAGING OF 2-MM ELLIPTICAL FATIGUE CRACK

- Sizing of defects possible even without a diffraction signal
- True-shape imaging of defects



D-Scan and TFM reconstruction

3 3−AXIS POLAR SCANNER FOR COMPOSITE INSPECTION

- 3-axis polar scanner motion can be read by GEKKO and transformed into a $\rm X,\ Y\ Cscan$ for composite inspection.



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SPECIFICATIONS

general

L x W x H: 410mm x 284mm x 126mm

Operating temperature range: from -10°C to 45°C | 14°F to 113°F Storage temperature range: -10°C to 60°C | 14°F to 140°F with battery

Phased array computation delay laws on plate, cylinder, T & Y, nozzle

Operating time: 4h (hot swappable battery)

10.4" high contrast resistive screen - resolution 1024x768 px

Weight: 6kg (without battery); 0,480g /battery

Shock resistance according to MIL-STD-810G

standard phased-array

Linear scanning, sectorial scanning, compound scanning

Maximum active aperture: 64 channels

Focusing mode: true depth, sound path, projection

Linear, matrix, DLA and DMA probes

Up to 6 probes | Up to 8 groups | Up to 2,048 delay-laws

CIVA fueled phased-array calculator

real-time TFM

Reconstruction channels: up to 64

Max refresh rate: up to 80fps

Max number of points of reconstructed image: up to 65k Sound paths: direct (L or S), indirect and converted modes

64 phased-array channels*:

Negative square pulse, width: 35ns to 1250ns

Voltage: 12V - 100V with 1V step

Max. PRF: up to 20kHz

4 UT-TOFD channels**:

Negative square pulse, width: 30ns to 1250ns

Voltage: 12V to 200V with 1V step

Max. PRF: up to 20kHz

receivers

64 phased-array channels*:

Input impedance: 50 Ω Frequency range: 0.4 to 20MHz

Max. input signal: 2Vpp | TCG - ACG - DGS calibration wizard | DGS

Gain: up to 120dB (0.1dB step)

Cross-talk between two channels < 50 dB

4 UT-TOFD channels**:

Input impedance: 50 Ω Frequency range: 0.6 to 25MHz Max. input signal: 2Vpp TCG - DAC calibration wizard

Gain: up to 120dB (0.1dB step)

digitizer

Digitizing and real-time summation on 64 channels

FIR filters

Real-time averaging up to x32 Rectified, RF, envelope

Resolution: 16bits

Max. sampling frequency: 100 MHz Digitizing depth up to 16k points

acquisition

Hardware acquisition gates

A-Scan/Peak data recording

FMC recording

Acquisition trigger on time, event, encoder

A-scan range or delay max 65k points

Inspection data file size: up to 10Gb Data transfer through Ethernet

wizards

CAD overlay and 3D view

Real-time phased array calculator Base-time calibration for conventional UT Wedge calibration (angle, height, velocity)

Specimen velocity calibration

800% amplitude range Scanner calibration

Amplitude calibration (TCG, DAC, DGS) Probe design | Weld geometry design

Amplitude balancing

Part geometry with parametric shapes: plate, cylinder, T & Y, nozzle

Max. data flow 150 MB/s on a 128Gb SSD (extensible up to 1 To)

analysis

Capture © software with analysis and reporting tools - Free viewer

A-Scan, B-Scan, C-Scan, D-Scan, Echodynamic, Top view, Side view, 3D view

Analysis gates

Compatibility with CIVA analysis and ENLIGHT

Amplitude range: up to 800%

Overlay part geometry: plate, cylinder, T or Y section, nozzle

Overlay weld geometry

Customizable inspection report

3 USB 2.0

1 IPEX connector for phased-array (can be upgraded to 2 with splitter)

4 LEMO 00 connectors for conventional UT

1 external trigger

Acquisition file transfer through Ethernet

16 analog inputs





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